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Customer Number

Patent
Case No.: 58355US002



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named Inventor: THEISS, STEVEN D
Application No.: 10/734684 Group Art Unit: 1765
Filed: December 12, 2003 Examiner: Unknown
Title: METHOD FOR PATTERNING FILMS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on:

July 2, 2004
Date

Hylis H. Froelke
Signed by: Hylis H. Froelke

Dear Sir:

Pursuant to 37 CFR §§ 1.56, 1.97, and 1.98, enclosed is a completed Form PTO-1449, citing references submitted for consideration by the Examiner. Copies of any cited foreign patents, non-patent literature, and unpublished US application documents are enclosed. Pursuant to the waiver in the Pre-OG Notice, dated July 11, 2003, copies of US patents and published US patent applications are no longer required and are not enclosed. It is respectfully requested that the Examiner initial and return the enclosed Form PTO-1449 to indicate that each reference has been considered.

If a first Office Action on the merits has been mailed prior to the mailing date of this document, please charge the fee for consideration of an Information Disclosure Statement set forth in 37 CFR § 1.17(p), and if necessary, please charge any additional fees, or credit any overpayment to Deposit Account No. 13-3723.

Respectfully submitted,

July 2, 2004
Date

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

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Application Number**10/734684****Filing Date****December 12, 2003****First Named Inventor****Theiss, Steven D****Art Unit****1765****Examiner Name****Attorney Case Number****58355US002****U.S. Patent Documents**

Exam. Init.*	Cite No.	Document Number	Publication Date or Issue Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Doc. Number-(Kind Code if Known)			
	A1	US- 5,536,319	07/16/96	Wary et al.	
	A2	US- 5,846,694	12/08/98	Strand et al.	
	A3	US- 6,087,270	07/11/00	Reinberg et al.	
	A4	US- 6,319,784 B1	11/20/01	Yu et al.	
	A5	US- 6,433,359	08/13/02	Kelley et al.	
	A6	US- 6,617,609	09/09/03	Kelley et al.	
	A7	US- 2002-0167067 A1	11/14/02	Kim	
	A8	US- 2003-0102471 A1	06/05/03	Kelley et al.	
	A9	US- 2003-0105365 A1	06/05/03	Smith et al.	
	A10	US- 2003-0100779 A1	05/29/03	Vogel et al.	
	A11	US- 2003-0150384 A1	08/14/03	Baude et al.	
	A12	US- 2003-0151118 A1	08/14/03	Baude et al.	
	A13	US- 2003-0152691 A1	08/14/03	Baude et al.	

OTHER DOCUMENTS

Exam. Init.*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	Translation (Check if yes)
	C1	S.M. Sze, Physics of Semiconductor Devices, 2 nd Ed., John Wiley and Sons, p. 492, New York (1981)	
	C2	NIST Special Publication 922 "Polycyclic Aromatic Hydrocarbon Structure Index," U.S. Govt. Printing Office, by Sander & Wise (1997)	
	C3	P. Reinig et al., "Crystalline Silicon Films Grown by Pulsed DC Magnetron Sputtering", J. Non-Crystalline Solids, 299-302, pp. 128-132 (2002)	
	C4	P.G. Carey, et al., "Polysilicon Thin-Film Transistors Fabricated on Low Temperature Plastic Substrates," J. Vac. Sci. Technol., A, 17(4) pp. 1946-49 (1999)	
	C5	U.S.S.N. 10/434,377, filed May 8, 2003, "Organic Polymers, Electronic Devices, and Methods" (Bai et al.)	
	C6	U.S.S.N. 10/620,027, filed July 15, 2003, "Bis[2-acenyl]Acetylene Semiconductors" (Gerlach)	
	C7	U.S.S.N. 10/642919, filed August 18, 2003, "Method for Sealing Thin Film Transistors" (Muyres et al.)	

Examiner:*Date Considered:**

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.